

SEM 2012

October 23-25, 2012, Göteborg, SWEDEN

Tuesday October 23, 2012

- 08.45 - 09.00** **Registration: outside Kollektorn**
- 09.00 - 12.15** **LECTURE HALL Kollektorn**
- 09.00 - 09.15 Welcome address and introductory remarks by the organizers
Peter Apell, Head of Department, Applied Physics, Chalmers
Lena Falk and Mats Halvarsson, Applied Physics, Chalmers
- 09.15 - 09.45 Technological solutions in the scanning electron microscope
Mats Eriksson, Spectral Solutions, Sweden
- 09.45 - 10.15 **COFFEE in the Canyon**
- 10.15 - 11.00 High resolution and low voltage scanning electron microscopy
Ed Boyes, University of York, UK
- 11.00 - 11.45 Variable pressure scanning electron microscopy
Brad Thiel, University at Albany, USA
- 11.45 - 11.50 **BREAK**
- 11.50 - 12.15 Electron backscatter diffraction
Keith Dicks, Oxford Instruments, UK
- 12.15 - 13.15** **LUNCH in the Canyon**
- 13.15 - 19.00** **PRACTICALS**
- 13.15 - 14.30 Demonstrations -- Session I
- 14.30 - 15.00 **COFFEE in the Canyon**
- 15.00 - 17.30 Demonstrations -- Session II
- 17.30 - 19.00 Open Lab
- 19.00** **COURSE DINNER at "Villan"**

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Wednesday October 24, 2012

- 09.00 - 12.00** **LECTURE HALL KOLLEKTORN**
- 09.00 - 09.10 Introductory remarks by the organizers
- 09.10 - 09.50 *In-situ* experiments in variable pressure instruments
Brad Thiel, University at Albany, USA
- 09.50 - 10.20 **COFFEE in the Canyon**
- 10.20 - 10.45 *In-situ* tensile testing
Julia Netrval, Spectral Solutions, Sweden
- 10.45 - 11.10 "Give your microscope a hand": *In-situ* manipulation
Bernd Volbert, Kleindiek Nanotechnik, Germany
- 11.10 - 11.20 **BREAK**
- 11.20 - 12.00 3D applications in dual beam instruments
Ellen Baken, FEI Company, The Netherlands
- 12.00 - 13.00** **LUNCH in the Canyon**
- 13.00 - 20.00** **PRACTICALS**
- 13.00 - 14.15 Demonstrations -- Session III
- 14.15 - 14.45 **COFFEE in the Canyon**
- 14.45 - 17.15 Demonstrations -- Session IV
- 17.15** **SANDWICHES and REFRESHMENTS**
- 17.15 - 20.00 Open Lab

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Thursday October 25, 2012

09.00 - 12.00 *LECTURE HALL KOLLEKTORN*

09.00 - 09.05 Introductory remarks by the organizers

09.05 - 09.45 XEDS at low voltages
Ed Boyes, University of York, UK

09.45 - 10.20 Low loss BSE contrast mechanisms in hybridisation and band gaps
Heiner Jaksch, Carl Zeiss NTS, Germany

10.20 - 10.50 **COFFEE**

10.50 - 11.25 Application examples of advanced EBSD/EDS integration
Daniel Goran, Bruker Nano GmbH, Germany

11.25 - 11.50 Mini - Laboratory -- Future trends in scanning electron microscopy
Patrick Woo, Hitachi High-Technologies, Canada

11.50 - 12.00 Concluding remarks by the organizers

12.00 - 13.00 *LUNCH in the CANYON*

13.00 - 15.30 *PRACTICALS*

13.00 - 14.15 Demonstrations -- Session V

14.15 - 14.30 **COFFEE**

14.30 - 15.45 Demonstrations -- Session VI

15.45 *End of Course*